Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/646,638	JOHN G. KURTH		
Examiner	Art Unit		
Benny Q. Tieu	2614		

SEAR Subclass	<b>CHED</b> Date	Examiner
Subclass	Date	Examiner
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	1/21/2007	BQT		